



6NM65-FDQ

Power MOSFET

6A, 650V N-CHANNEL SUPER-JUNCTION MOSFET

■ DESCRIPTION

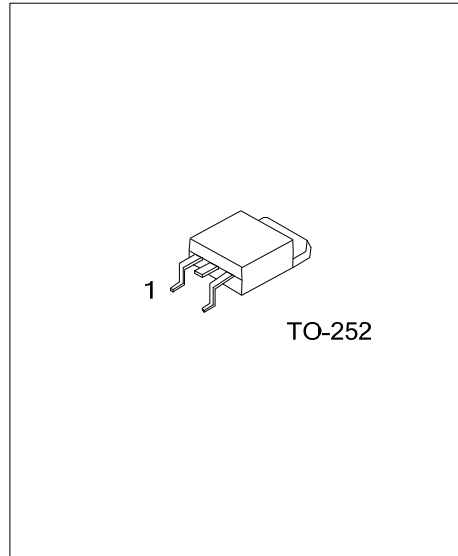
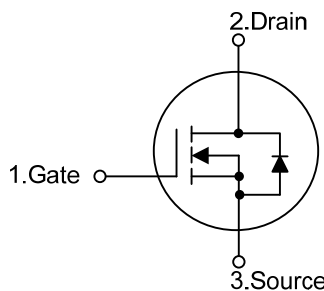
The UTC **6NM65-FDQ** is a Super Junction MOSFET Structure. It uses UTC advanced planar stripe, DMOS technology to provide customers perfect switching performance, minimal on-state resistance.

The UTC **6NM65-FDQ** is universally applied in electronic lamp ballasts based on half bridge topology, high efficiency switched mode power supplies, active power factor correction, etc.

■ FEATURES

- * $R_{DS(on)} < 1.2 \Omega @ V_{GS}=10V, I_D=3.0A$
- * Improved dv/dt capability
- * Fast switching
- * 100% avalanche tested

■ SYMBOL



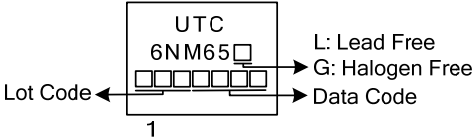
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
6NM65L-TN3-R	6NM65G-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>6NM65G-TN3-R</p> <p>(1)Packing Type</p> <p>(2)Package Type</p> <p>(3)Green Package</p>	<p>(1) R: Tape Reel</p> <p>(2) TN3: TO-252</p> <p>(3) G: Halogen Free and Lead Free L: Lead Free</p>
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MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	650	V
Gate-Source Voltage		V_{GSS}	± 30	V
Drain Current	Continuous	I_D	6	A
	Pulsed (Note 2)	I_{DM}	18	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	200	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	8	V/ns
Power Dissipation		P_D	55	W
Junction Temperature		T_J	+150	$^\circ\text{C}$
Storage Temperature		T_{STG}	-55 ~ +150	$^\circ\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating : Pulse width limited by maximum junction temperature.

3. $L=100\text{mH}$, $I_{AS}=2.0\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\ \Omega$, Starting $T_J = 25^\circ\text{C}$

4. $I_{SD}\leq 6.0\text{A}$, $di/dt\leq 200\text{A}/\mu\text{s}$, $V_{DD}\leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	110	$^\circ\text{C}/\text{W}$
Junction to Case	θ_{JC}	2.27	$^\circ\text{C}/\text{W}$

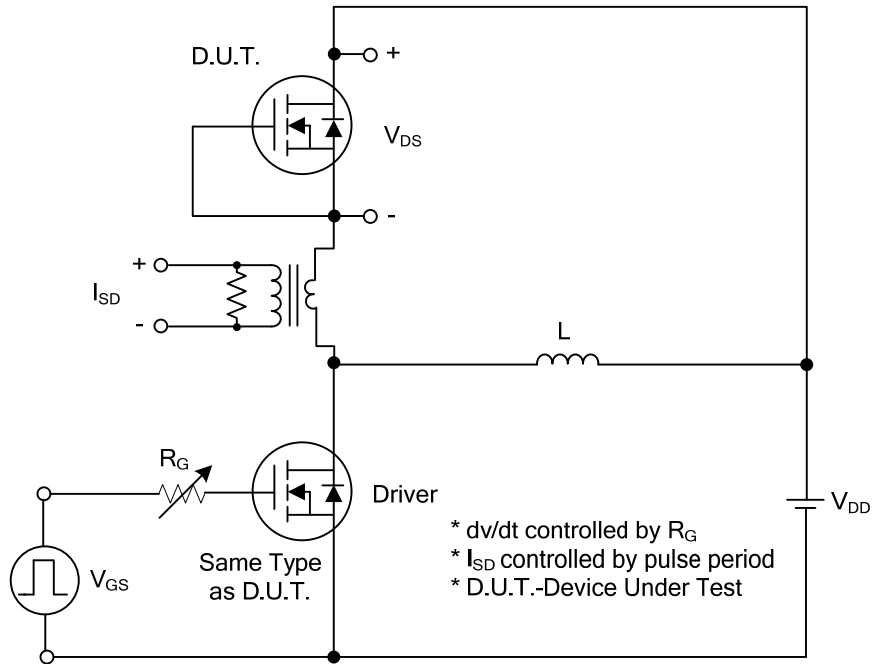
■ ELECTRICAL CHARACTERISTICS ($T_C=25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	$V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$	650			V
Drain-Source Leakage Current		I_{DSS}	$V_{DS} = 650\text{V}$, $V_{GS} = 0\text{V}$			10	μA
Gate-Source Leakage Current	Forward	I_{GSS}	$V_{GS} = 30\text{V}$, $V_{DS} = 0\text{V}$			100	nA
	Reverse		$V_{GS} = -30\text{V}$, $V_{DS} = 0\text{V}$			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	2.5		4.5	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	$V_{GS} = 10\text{V}$, $I_D = 3.0\text{A}$			1.2	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C_{ISS}	$V_{GS}=0\text{V}$, $V_{DS}=25\text{V}$, $f=1.0\text{MHz}$		340		pF
Output Capacitance		C_{OSS}			280		pF
Reverse Transfer Capacitance		C_{RSS}			30		pF
SWITCHING CHARACTERISTICS							
Turn-ON Delay Time (Note 1)		$t_{D(ON)}$	$V_{DD}=300\text{V}$, $V_{GS}=10\text{V}$, $I_D=6.0\text{A}$, $R_G=25\Omega$ (Note 1, 2)		1.2		nS
Rise Time		t_R			12		nS
Turn-OFF Delay Time		$t_{D(OFF)}$			33		nS
Fall-Time		t_F			19		nS
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS							
Maximum Body-Diode Continuous Current		I_S				6	A
Maximum Body-Diode Pulsed Current		I_{SM}				18	A
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	$I_S=6.0\text{A}$, $V_{GS}=0\text{V}$			1.4	V
Body Diode Reverse Recovery Time (Note 1)		t_{rr}	$I_S=6.0\text{A}$, $V_{GS}=0\text{V}$,		160		nS
Body Diode Reverse Recovery Charge		Q_{rr}	$di_f/dt=100\text{A}/\mu\text{s}$		1		μC

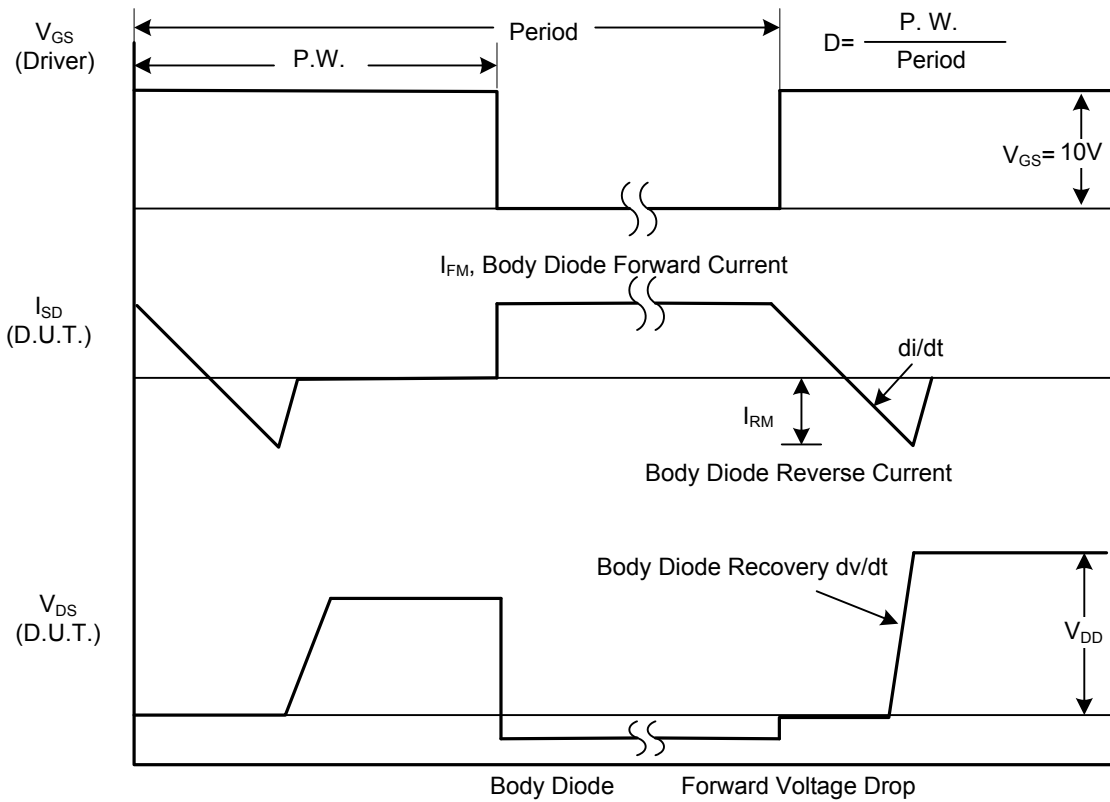
Notes: 1. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$

2. Essentially independent of operating ambient temperature

TEST CIRCUITS AND WAVEFORMS

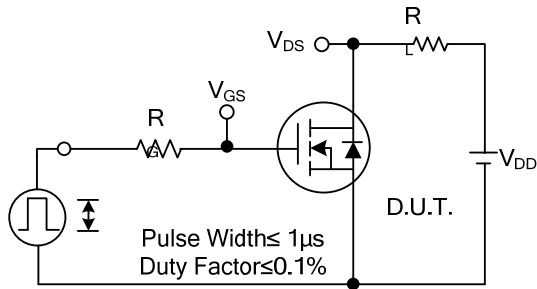


Peak Diode Recovery dv/dt Test Circuit

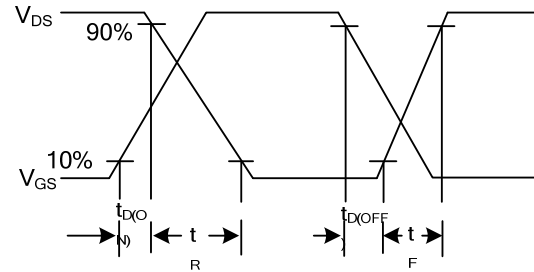


Peak Diode Recovery dv/dt Waveforms

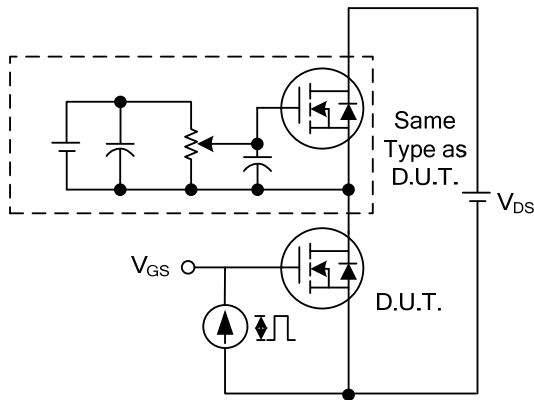
TEST CIRCUITS AND WAVEFORMS



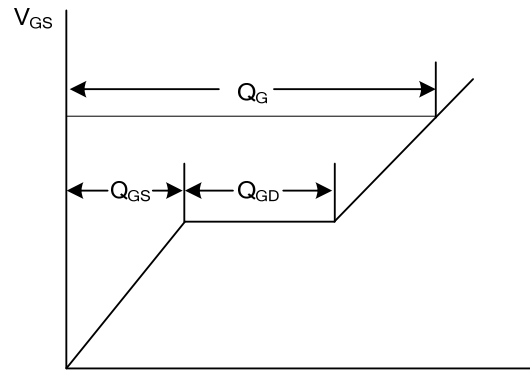
Switching Test Circuit



Switching Waveforms

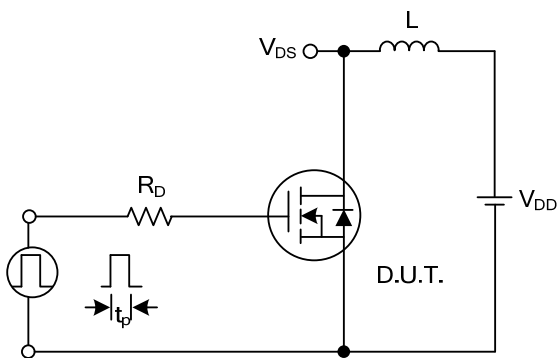


Gate Charge Test Circuit

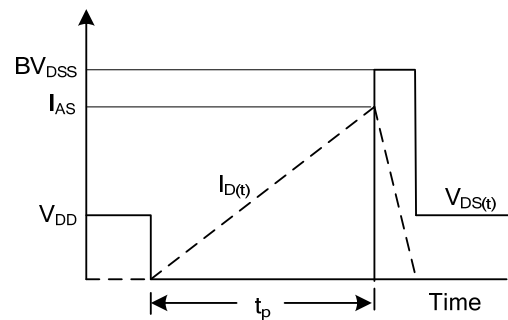


Charge

Gate Charge Waveform

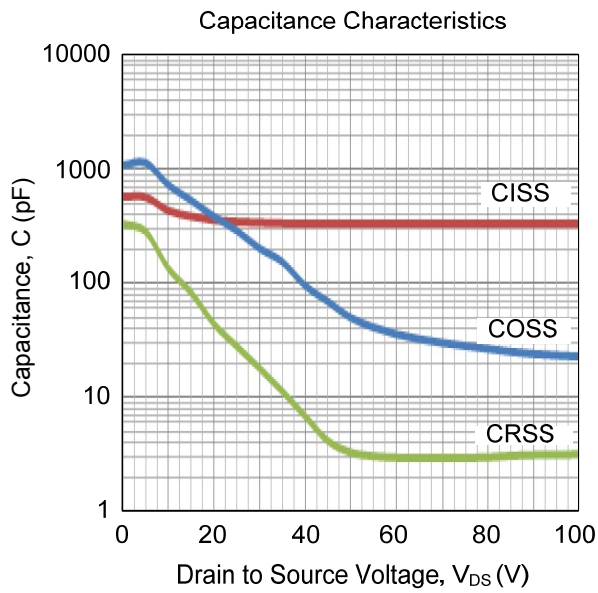


Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

■ TYPICAL CHARACTERISTICS



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